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Application/Control No.	Applicant(s)/Patent under Reexamination	_
10/565,328	MAIER ET AL.	
Examiner	Art Unit	
Patrick D. Niland	1714	

SEARCHED			
Class	Subclass	Date	Examiner
524	507 591 839 840	1/2/2007	PN

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EAST and Inventor Name searches in file	1/2/2007	PN
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